

#### PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
2783	SSF2783	TSOP-6	—	—	—

#### ABSOLUTE MAXIMUM RATINGS(TA=25°C unless otherwise noted)

Parameter		Symbol	N-Channel	P-Channel	Unit	
Drain-Source Voltage		V <sub>DS</sub>	20	-20	V	
Gate-Source Voltage		V <sub>GS</sub>	±8	±8	V	
Continuous Drain Current	T <sub>A</sub> =25℃	- I <sub>D</sub> -	3.5	-2.7	А	
Continuous Drain Current	T <sub>A</sub> =70℃		2.4	-1.8	A	
Pulsed Drain Current (Note 1)		I <sub>DM</sub>	11	-8	А	
Maximum Rower Dissinction	T <sub>A</sub> =25℃	D	1.1	1.1	W	
Maximum Power Dissipation	T <sub>A</sub> =70℃	P <sub>D</sub>	0.6	0.6	vV	
Operating Junction and Storage Temperature Range		T <sub>J</sub> ,T <sub>STG</sub>	-55 To 150	-55 To 150	°C	

#### THERMAL CHARACTERISTICS

Thermal Resistance, Junction-to-Ambient (Note2)	Den	N-Ch	87	°C/W	
	R <sub>0JA</sub>	P-Ch	87	0.100	



Parameter	Symbol	Condition		Min	Тур	Мах	Uni
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	D) (	V <sub>GS</sub> =0V I <sub>D</sub> =250µA	N-Ch	20			- V
	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =-250µA	P-Ch	-20			
Zana Oata Maltana Daalia Ourrant		V <sub>DS</sub> =20V,V <sub>GS</sub> =0V	N-Ch			1	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =-20V,V <sub>GS</sub> =0V	P-Ch			-1	μA
		$V_{GS}$ =±8V, $V_{DS}$ =0V	N-Ch			±100	1.
Gate-Body Leakage Current	I <sub>GSS</sub>		P-Ch			±100	nA
ON CHARACTERISTICS (Note 3)			·				
Cata Throphold Valtage	V	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$	N-Ch	0.6		1	v
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS}=V_{GS}$ , $I_{D}=-250\mu A$	P-Ch	-0.6		-1	
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =3.5A	N-Ch		41	60	
		$V_{GS}$ =-4.5V, I <sub>D</sub> =-2.7A	P-Ch		83	100	- - mΩ -
Desia Osuma Os Otata Dasistanas		V <sub>GS</sub> =2.5V, I <sub>D</sub> =2.9A	N-Ch		51	90	
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =-2.5V, I <sub>D</sub> =-2.4A	P-Ch		110	145	
		V <sub>GS</sub> =1.8V, I <sub>D</sub> =2.2A	N-Ch		67	150	
		V <sub>GS</sub> =-1.8V, I <sub>D</sub> =-1.9A	P-Ch		140	220	
		V <sub>DS</sub> =10V,I <sub>D</sub> =3.5A	N-Ch		10		s
Forward Transconductance	<b>g</b> fs	V <sub>DS</sub> =-10V,I <sub>D</sub> =-2.7A	P-Ch		9		
SWITCHING CHARACTERISTICS (No	te 4)						•
Furn on Dolov Time		N-Ch V <sub>DD</sub> =10V, I <sub>D</sub> =1A V <sub>GEN</sub> =4.5V,R <sub>GEN</sub> =6Ω	N-Ch		6.5		nS nS
Furn-on Delay Time	t <sub>d(on)</sub>		P-Ch		10		
			N-Ch		4		
Turn-on Rise Time	t <sub>r</sub>		P-Ch		6		
		P-Ch V <sub>DD</sub> =-10V, I <sub>D</sub> =-1A	N-Ch		16		nS
Furn-Off Delay Time	$t_{d(off)}$		P-Ch		33		
		$V_{GEN}$ =-4.5V, $R_{GEN}$ =6 $\Omega$	N-Ch		3		– nS
Turn-Off Fall Time	t <sub>f</sub>		P-Ch		29		
OYNAMIC CHARACTERISTICS (Note	4)						
	C <sub>lss</sub>	N-Ch V <sub>DS</sub> =10V,V <sub>GS</sub> =0V,	N-Ch		380		– PF
Input Capacitance			P-Ch		500		
Output Capacitance	C <sub>oss</sub>	F=1.0MHz P-Ch	N-Ch		70		- PF
			P-Ch		80		
		P-Cn V <sub>DS</sub> =10V,V <sub>GS</sub> =0V, F=1.0MHz	N-Ch		40		PF
Reverse Transfer Capacitance	C <sub>rss</sub>		P-Ch		45		



Tatal Cata Charge	Qg	N-Ch	N-Ch		4.6		nC
Total Gate Charge		V <sub>DS</sub> =10V,I <sub>D</sub> =2A,	P-Ch		6		nc
Gate-Source Charge	0	V <sub>GS</sub> =4.5V	N-Ch		0.9		nC
Gale-Source Charge	$Q_gs$	P-Ch	P-Ch		1.1		
Gate-Drain Charge	Q <sub>gd</sub>	V <sub>DS</sub> =-10V,I <sub>D</sub> =-1A, V <sub>GS</sub> =-4.5V	N-Ch		0.8		nC
			P-Ch		1.2		IIC.
DRAIN-SOURCE DIODE CHARACTERISTICS							
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =0.8A	N-Ch		0.7	1.2	V
		V <sub>GS</sub> =0V,I <sub>S</sub> =-0.8A	P-Ch		-0.7	-1.2	V

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## NOTES:

Repetitive Rating: Pulse width limited by maximum junction temperature.
Surface Mounted on FR4 Board, t ≤ 10 sec.
Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.
Guaranteed by design, not subject to production testing.



# N-Channel THERMAL CHARACTERISTICS

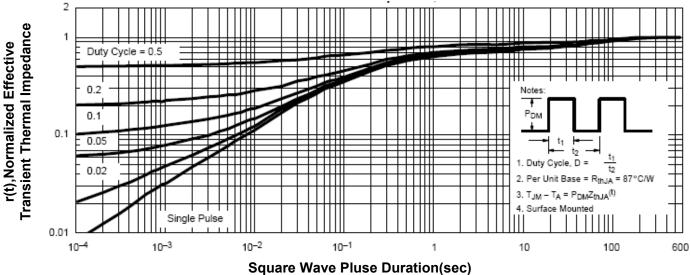
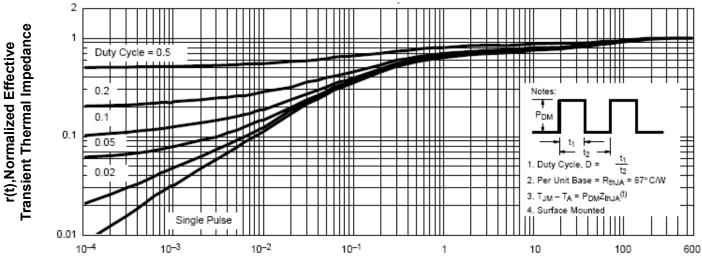


Figure 1: Normalized Maximum Transient Thermal Impedance

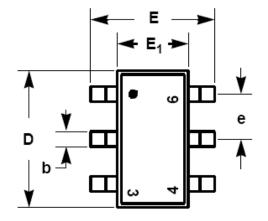
# P-Channel THERMAL CHARACTERISTICS

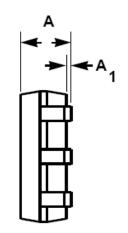


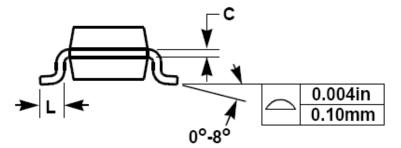
Square Wave Pluse Duration(sec) Figure 2: Normalized Maximum Transient Thermal Impedance

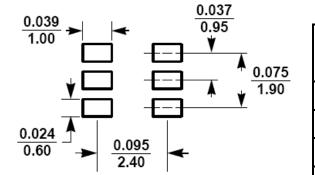


# **TSOP-6 PACKAGE INFORMATION**









SYMBOL	Millimeters				
STMBOL	MIN	MAX			
А	0.90 1.10				
A1	0.10				
b	0.30	0.50			
С	0.08 0.20				
D	2.70 3.10				
E	2.60 3.00				
E1	1.40 1.80				
e	0.95 BSC				
L	0.35 0.55				

## NOTES:

1. Dimensions are inclusive of plating

2. Package body sizes exclude mold flash and gate burrs. Mold flash at the non-lead sides should be less than 6 mils.

Dimension L is measured in gauge plane.
Controlling dimension is millimeter, converted inch dimensions are not necessarily exact.



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